

PATENT ASSIGNMENT COVER SHEET

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EPAS ID: PAT5941794

SUBMISSION TYPE:	NEW ASSIGNMENT
NATURE OF CONVEYANCE:	ASSIGNMENT
CONVEYING PARTY DATA	
Name	Execution Date
CHUNG CHENG HOLDINGS, LLC	11/26/2019
RECEIVING PARTY DATA	
Name:	INTELLECTUAL VENTURES ASSETS 158 LLC
Street Address:	251 LITTLE FALLS DRIVE
City:	WILMINGTON
State/Country:	DELAWARE
Postal Code:	19808
PROPERTY NUMBERS Total: 15	
Property Type	Number
Patent Number:	5770474
Patent Number:	6015742
Patent Number:	6020597
Patent Number:	6028000
Patent Number:	6080615
Patent Number:	6083833
Patent Number:	6090652
Patent Number:	6127197
Patent Number:	6462565
Patent Number:	6146999
Patent Number:	6204100
Patent Number:	6531742
Patent Number:	6340541
Patent Number:	6730528
Application Number:	10793743
CORRESPONDENCE DATA	
Fax Number:	(404)645-7707
<i>Correspondence will be sent to the e-mail address first; if that is unsuccessful, it will be sent using a fax number, if provided; if that is unsuccessful, it will be sent via US Mail.</i>	
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PATENT

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ATTORNEY DOCKET NUMBER:	11206-001GEN
NAME OF SUBMITTER:	LAWRENCE A. AARONSON
SIGNATURE:	/Lawrence A. Aaronson/
DATE SIGNED:	02/01/2020

Total Attachments: 10

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ASSIGNMENT OF RIGHTS IN CERTAIN ASSETS

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KR10-0268906 (KR10-1997-0049794)	KR	7/18/2000 (9/29/1997)	Method For Forming Inductor Of Semiconductor Device Ju, Jae-II
6015742 (09/053500)	US	1/18/2000 (4/2/1998)	Method For Fabricating Inductor Of Semiconductor Device Unable to Verify
DE19806017.3 (DE19806017.3)	DE	5/11/2006 (2/13/1998)	Semiconducting Multi-Chip Module Kwak, Duk Joo
JP2847516 (JP10-049570)	JP	11/6/1998 (3/2/1998)	Semiconductor Multi-Chip Module Kwak, Duk Joo

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KR10-0214560 (KR10-1997-0007164)	KR	5/20/1999 (3/5/1997)	Semiconductor Multi Chip Module Kwak, Duk-Joo
JP3182608 (JP09-315981)	JP	4/27/2001 (10/31/1997)	Method Of Forming Contact Plugs Of Semiconductor Device Having Contact Holes Different In Size Cho, Gyung-Su
KR10-0214852 (KR10-1996-0051690)	KR	5/20/1999 (11/2/1996)	Forming Method For Metal Wiring In Semiconductor Device Cho, Kyong-Soo
6028000 (08/960899)	US	2/22/2000 (10/30/1997)	Method Of Forming Contact Plugs In Semiconductor Device Having Different Sized Contact Holes Cho, Gyung-Su
TW1119581 (TW086116228)	TW	9/1/2000 (10/30/1997)	Method Of Forming Contact Plugs In Semiconductor Device Having Different Sized Contact Holes Cho, Gyung-Su
JP3740272 (JP10-066562)	JP	11/11/2005 (3/17/1998)	Manufacture Of IC For Communication Device Unable to Verify
KR10-0198663 (KR10-1997-0008970)	KR	3/2/1999 (3/17/1997)	Forming Method Of IC For Communication Lee, Chang-Jae
6080615 (09/002679)	US	6/27/2000 (1/5/1998)	Method For Forming A Semiconductor Device Incorporating A Dummy Gate Electrode Lee, Chang-Jae
6083833 (09/097680)	US	7/4/2000 (6/16/1998)	Method For Forming Conductive Film For Semiconductor Device Unable to Verify
(JP10-175610)	JP	(6/23/1998)	Formation Of Conductive Film An, Min-Soo

Patent or Application No.	Country	Grant Date Filing Date	Title of Patent and First Named Inventor
KR10-0244484 (KR10-1997-0030596)	KR	11/22/1999 (7/2/1997)	Method For Fabricating A Semiconductor Device An, Min-Soo
JP2964232 (JP09-367428)	JP	8/13/1999 (12/25/1997)	Manufacture Of Semiconductor Device Kim, Jae-Kap
6090652 (08/996011)	US	7/18/2000 (12/22/1997)	Method Of Manufacturing A Semiconductor Device Including Implanting Threshold Voltage Adjustment Ions Kim, Jae-Kap
KR10-0220252 (KR10-1996-0075454)	KR	6/21/1999 (12/28/1996)	Method Of Manufacturing Semiconductor Device Kim, Jae-Kap
TW1102256 (TW086117308)	TW	4/11/1999 (11/19/1997)	Manufacturing Method Of A Semiconductor Device Kim, Jae Kap
GB2326721 (GB9813658.3)	GB	1/9/2002 (6/24/1998)	Wire Width Measurement Unable To Verify
JP3636800 (JP10-180838)	JP	1/14/2005 (6/26/1998)	Line Width Measurement For Wiring Pattern Of Semiconductor Element And Line Width Measuring Method Using The Same Unable To Verify
TW1110327 (TW087110031)	TW	1/11/2000 (6/22/1998)	Measuring-Pattern And Measuring Method For Width Of Wire In Semiconductor Device Kim, Kil-Ho
6127197 (09/104716)	US	10/3/2000 (6/25/1998)	Method For Measuring Width Of Wire In Semiconductor Device Using Measuring-Pattern Unable to Verify
6462565 (09/644992)	US	10/8/2002 (8/24/2000)	Measuring-Pattern For Measuring Width Of Wire In Semiconductor Device Unable to Verify
KR10-0272659 (KR10-1997-0028813)	KR	8/28/2000 (6/28/1997)	Pattern For Measuring Line Width Of A Metal Line Of A Semiconductor Device And Method For Measuring The Same

<u>Patent or Application No.</u>	<u>Country</u>	<u>Grant Date Filing Date</u>	<u>Title of Patent and First Named Inventor</u>
			Unable to Verify
JP2942231 (JP10-010183)	JP	6/18/1999 (1/22/1998)	Method For Forming Wiring Of Semiconductor Element Unable to Verify
6146999 (08/956387)	US	11/14/2000 (10/23/1997)	Method For Forming Metal Line Of Semiconductor Device Unable to Verify
KR10-0236076 (KR10-1997-0038880)	KR	9/29/1999 (8/14/1997)	Method For Forming Metal Wiring In Semiconductor Device Kang, Dong-Man
CNZL98123955.2 (CN98123955.2)	CN	4/14/2004 (11/6/1998)	CMOS Device And Method For Fabricating The Same Kim, Sang Yeon
KR10-0331844 (KR10-1998-0004190)	KR	3/26/2002 (2/12/1998)	Complementary Metal Oxide Semiconductor Device Kim, Sang Yeon
6204100 (09/249314)	US	3/20/2001 (2/12/1999)	CMOS Device And Method For Fabricating The Same Kim, Sang Yeon
6531742 (09/745555)	US	3/11/2003 (12/26/2000)	Method Of Forming CMOS Device Kim, Sang Yeon
GB2332534 (GB9824540.0)	GB	11/3/1999 (11/9/1998)	A Mask For Fabricating A Semiconductor Device And Method Thereof Yoo, Seung Seok
6340541 (09/140459)	US	1/22/2002 (8/26/1998)	Mask For Recycling And Fabrication Method Thereof Yoo, Seung Seok
KR10-0253381 (KR10-1997-0070071)	KR	1/22/2000 (12/17/1997)	Recycling Mask And Method For Manufacturing And Recycling The Same Yoo, Seung Seok
TW1110176 (TW087106993)	TW	12/11/1999 (5/6/1998)	Mask For Recycling And Fabrication Method Thereof Yoo, Seung Seok

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KR10-0223272 (KR10-1996-0074999)	KR	7/8/1999 (12/28/1996)	Overlap Measuring Marks And Method For Compensating Overlap Using The Same Park, Gi Yeop

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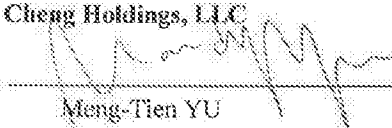
Assignor hereby authorizes the respective patent office or governmental agency in each jurisdiction to make available to Assignee all records regarding the Certain Assets.

The terms and conditions of this Assignment of Rights in Certain Assets will inure to the benefit of Assignee, its successors, assigns, and other legal representatives and will be binding upon Assignor, its successors, assigns, and other legal representatives.

DATED this 26th day of November 2019,

ASSIGNOR:

Chung Cheng Holdings, LLC

By: 

Name: Meng-Tien YU

Title: Authorized Person

ASSIGNEE:

Intellectual Ventures Assets 158 LLC

By:

Name: Lawrence Froeber

Title: Chief Financial Officer

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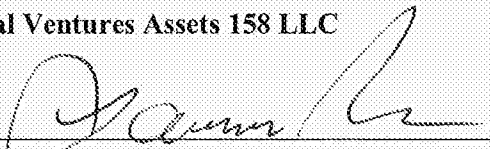
ASSIGNOR:

Chung Cheng Holdings, LLC

By: _____
Name: _____
Title: _____

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Intellectual Ventures Assets 158 LLC

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Title: Chief Financial Officer